

40V 10.5mohm P-channel Trench MOSFET
AKT4P100KL-A

Description:

This P channel Trench MOSFET has been designed to very low on-state resistance ($R_{DS(ON)}$), suggested use for Load Switch, PWM application Power management and general-purpose applications. Qualified AEC-Q101, PPAP capable.

Features:

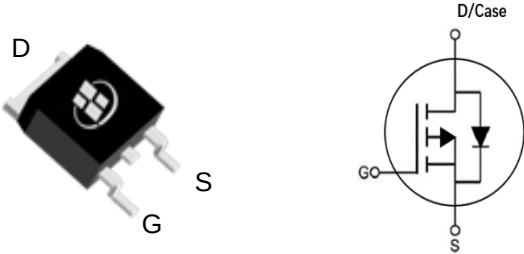
- Low $R_{DS(ON)}$
- RoHS compliant
- Halogen-free
- AEC-Q101 Qualified and PPAP capable

Applications:

- Load Switch
- Power Management
- DC-DC Converter

Key Performance Parameters:

Parameter	Value	Unit
V_{DS}	-40	V
$R_{DS(ON)}$, max @ $V_{GS} = -10\text{ V}$	10.5	m Ω
I_D	-68	A



Ordering Information:

Ordering Code	Package Type	Marking Code	Form	Packing
AKT4P100KL-A	TO-252	T4P100KL	Tape Reel	See the detail package information

Maximum Ratings (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Value	Units
V _{DS}	Drain-Source Voltage	-40	V
I _D	Drain Current - Continuous (T _C = 25°C) ^(Note 1)	-68	A
	Drain Current - Continuous (T _C = 100°C)	-48	A
I _{DM}	Drain Current - Pulsed ^(Note 2)	-272	A
V _{GS}	Gate-Source Voltage	±20	V
E _{AS}	Single Pulsed Avalanche Energy ^(Note 3)	182	mJ
P _D	Power Dissipation (T _C = 25°C)	88	W
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +175	°C

Thermal Characteristics

Symbol	Parameter	Value	Units
R _{θJC}	Thermal Resistance, Junction-to-Case, Steady-State	1.7	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient, Steady State ^(Note 4)	60	°C/W

Notes:

1. The max drain current rating is silicon limited
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. L = 0.5 mH, V_{DD} = -20 V, I_{AS} = -27 A, R_g = 50 Ω, Starting T_J = 25 °C
4. Mount on minimum PCB layout

Electrical Characteristics (T _J = 25°C unless otherwise noted)						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Static Characteristics						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = -250 μA	-40			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -40 V, V _{GS} = 0 V,			-1	μA
I _{GSS}	Gate Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
V _{GS(th)}	Gate Threshold voltage	V _{DS} = V _{GS} , I _D = -250 μA	-1	-1.7	-2.5	V
R _{DS(ON)}	Drain-Source on-state resistance	V _{GS} = -10 V, I _D = -30 A		7.7	10.5	mΩ
	Drain-Source on-state resistance	V _{GS} = -4.5 V, I _D = -30 A		10.3	16.5	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = -20 V, V _{GS} = 0 V, f = 1 MHz		5330		pF
C _{oss}	Output Capacitance			360		pF
C _{rss}	Reverse Transfer Capacitance			320		pF
R _g	Gate Resistance	f = 1 MHz		6.4		Ω
Switching Characteristics						
t _{d(on)}	Turn On Delay Time	V _{DD} = -32 V , I _D = -30 A, V _{GS} = -10 V, R _G = 10 Ω		14		ns
t _r	Rise Time			78		ns
t _{d(off)}	Turn Off Delay Time			207		ns
t _f	Fall Time			109		ns
Q _g	Total Gate Charge	V _{DD} = -32 V , I _D = -30 A, V _{GS} = -10 V		72		nC
Q _{gs}	Gate-Source Charge			22		nC
Q _{gd}	Gate-Drain Charge			25		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Body-Diode Forward Current				-68	A
I _{SM}	Maximum Pulsed Body-Diode Forward Current				-272	A
V _{SD}	Diode Forward Voltage	V _{GS} = 0 V, I _S = -30 A		-0.9		V
t _{rr}	Reverse recovery time	V _{DD} = -32 V, I _D = -30 A, di/dt = 100 A/μs		27		ns
Q _{rr}	Reverse recovery charge			28		nC
I _{rrm}	Peak Reverse Recovery Current			-1.9		A

Electrical Characteristics Diagrams

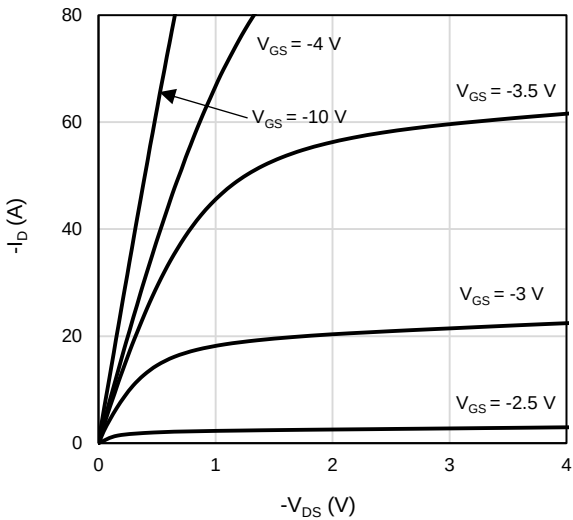


Figure 1: On-Region Characteristics

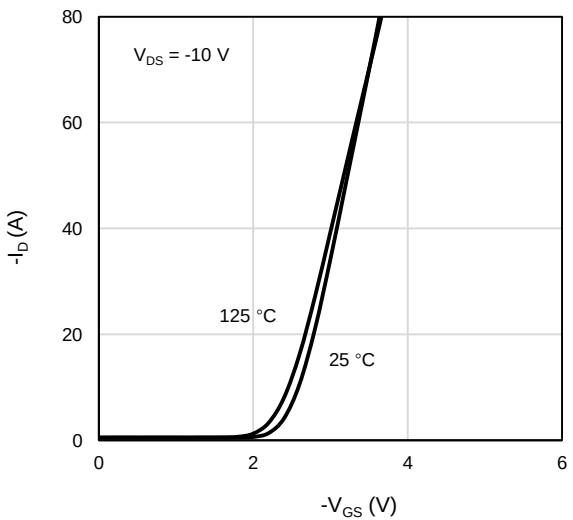


Figure 2: Transfer Characteristics

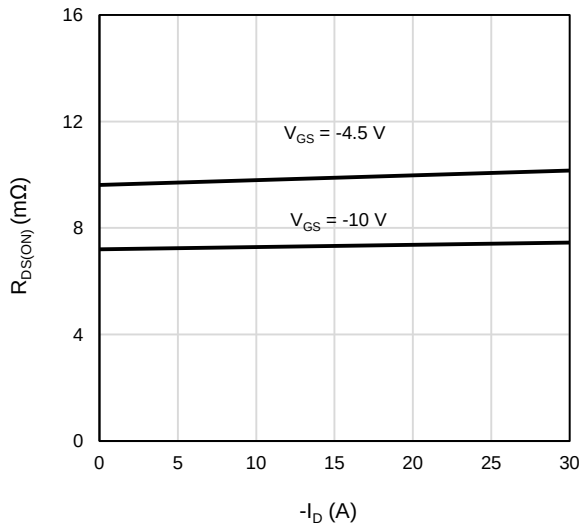


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

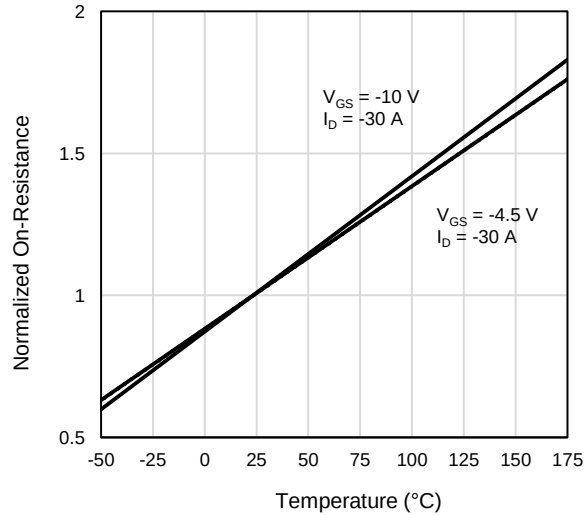


Figure 4: On-Resistance vs. Junction Temperature

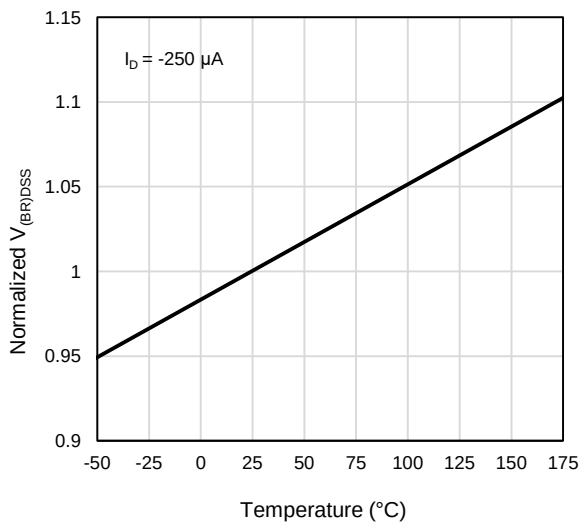


Figure 5: Breakdown Voltage vs. Junction Temperature

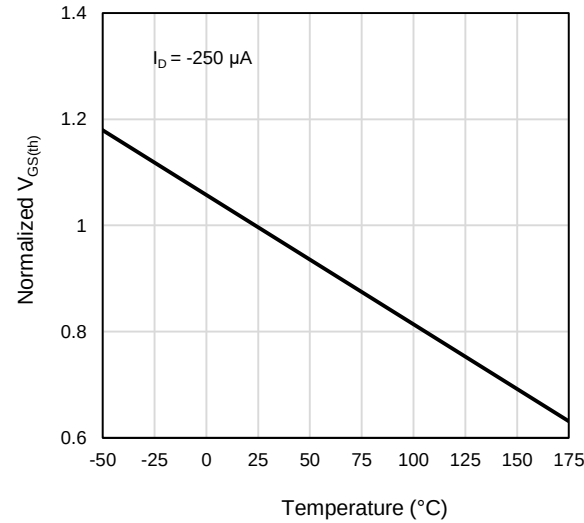


Figure 6: Threshold Voltage vs. Junction Temperature

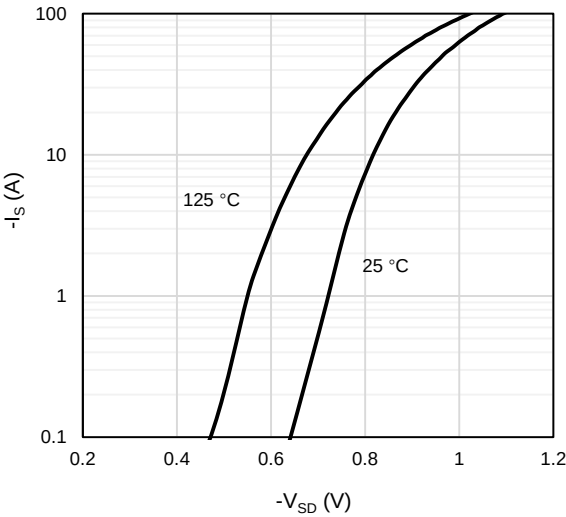


Figure 7: Body-Diode Characteristics

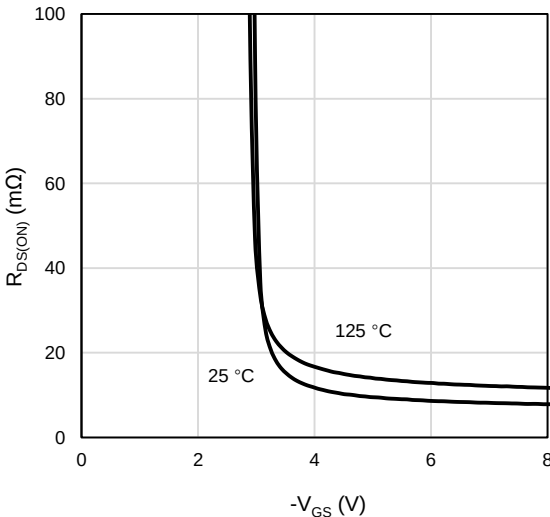


Figure 8: On-Resistance vs. Gate-Source Voltage

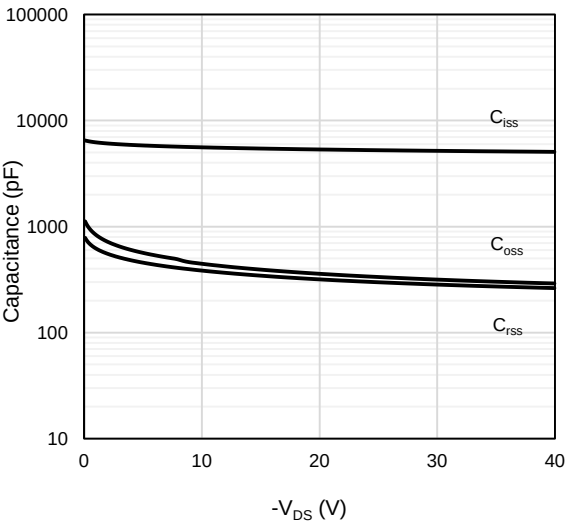


Figure 9: Capacitance Characteristics

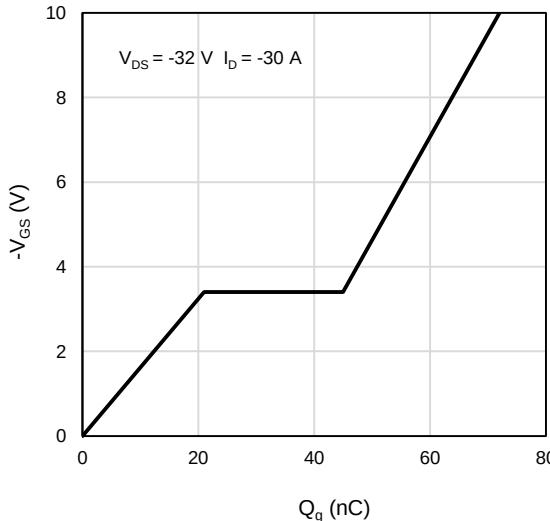


Figure 10: Gate-Charge Characteristics

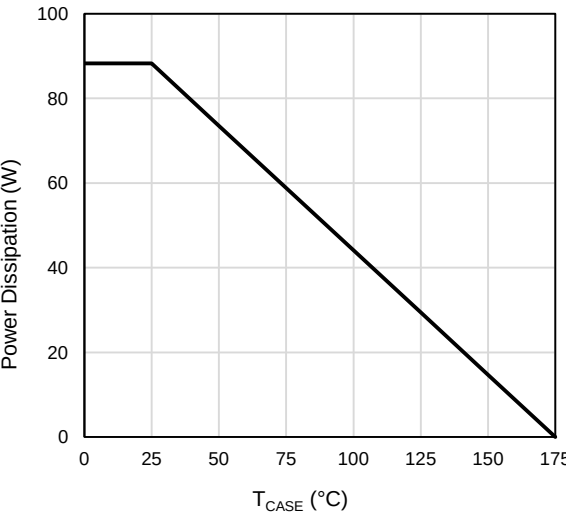


Figure 11: Power De-rating

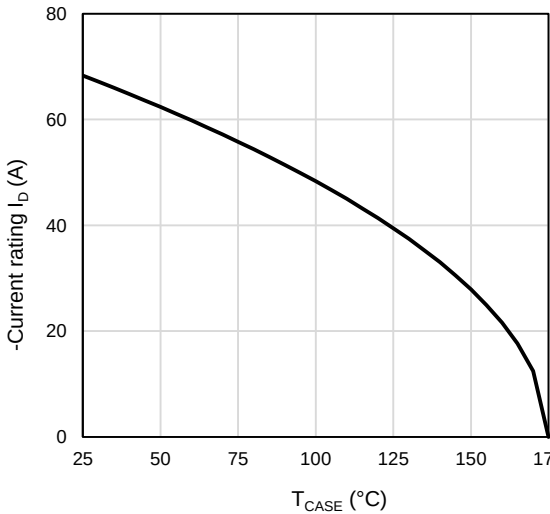


Figure 12: Current De-rating

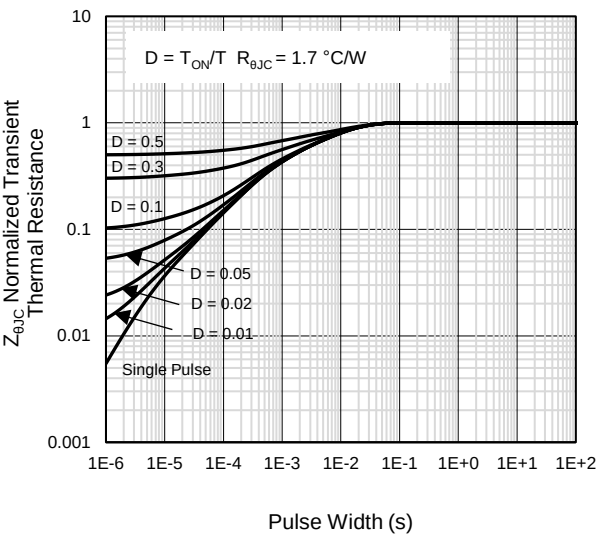


Figure 13: Normalized Maximum Transient Thermal Impedance

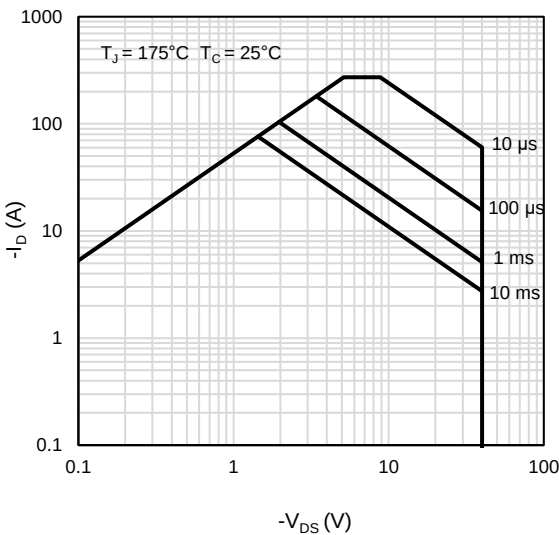
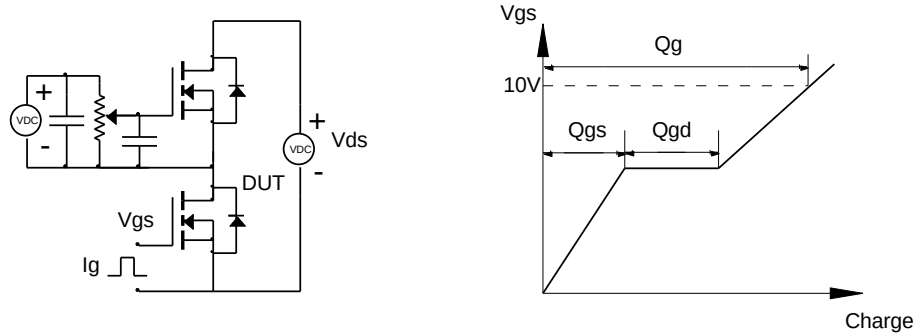


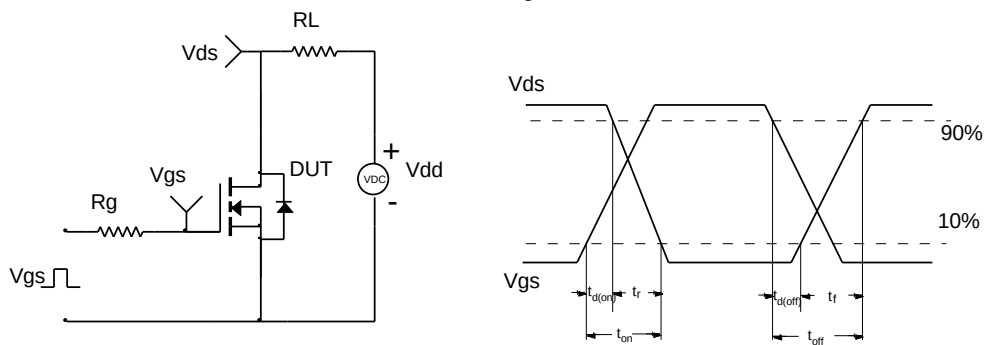
Figure 14: Maximum Forward Biased Safe Operating Area

Test Circuit and Waveform

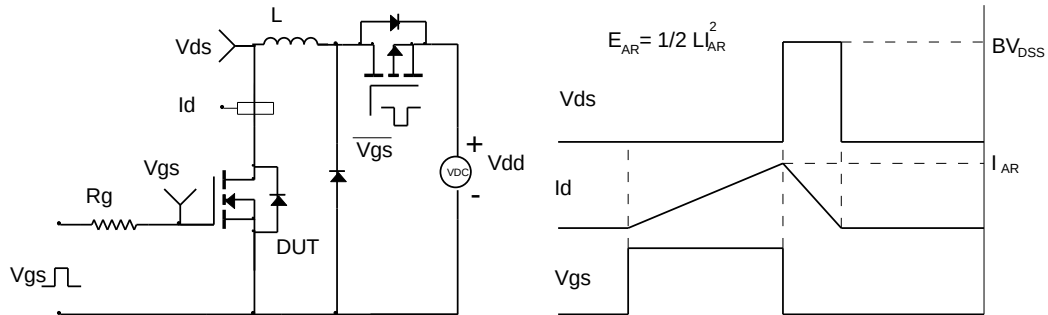
Gate Charge Test Circuit & Waveform



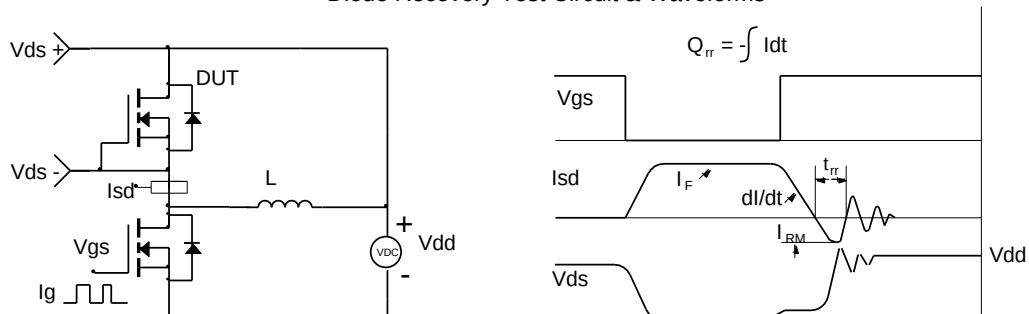
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Revision History

Revision	Released	Remark
Rev.1.2	2025	

Disclaimer

The information given in this document describes the independent performance of the product, but similar performance is not guaranteed under other working conditions, and cannot be guaranteed when installed with other products or equipment. To achieve the required performance of the product in actual scenarios, the customer should conduct a complete application test to assess the functionality of the product.

Alkaidsemi assumes no responsibility for equipment failures result from using products at values that exceed the ratings, operating conditions, or other parameters listed in the product specifications.

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